## 8-Input Data Selector/Multiplexer with 3-State Outputs <br> High-Speed Silicon-Gate CMOS

The IN74ACT251 is identical in pinout to the LS/ALS251, HC/HCT251. The IN74ACT251 may be used as a level converter for interfacing TTL or NMOS outputs to High Speed CMOS inputs.

The device selects one of the eight binary Data Inputs, as determined by the Address Inputs. The Output Enable pin must be at a low level for the selected data to appear at the outputs. If Output Enable is high, the Y and the $\overline{\mathrm{Y}}$ outputs are in the high-impedance state. This 3-State feature allows the IN74ACT251 to be used in busoriented systems.

- TTL/NMOS Compatible Input Levels
- Outputs Directly Interface to CMOS, NMOS, and TTL
- Operating Voltage Range: 4.5 to 5.5 V
- Low Input Current: $1.0 \mu \mathrm{~A} ; 0.1 \mu \mathrm{~A} @ 25^{\circ} \mathrm{C}$
- Outputs Source/Sink 24 mA


PIN $16=V_{\text {CC }}$
PIN $8=$ GND


PIN ASSIGNMENT


FUNCTION TABLE

| Inputs |  |  |  | Outputs |  |
| :---: | :---: | :---: | :---: | :---: | :---: |
| A2 | A1 | A0 | Output <br> Enable | Y | $\overline{\mathrm{Y}}$ |
| X | X | X | H | Z | Z |
| L | L | L | L | D0 | $\overline{\mathrm{D} 0}$ |
| L | L | H | L | D1 | $\overline{\mathrm{D} 1}$ |
| L | H | L | L | D2 | $\overline{\mathrm{D} 2}$ |
| L | H | H | L | D3 | $\overline{\mathrm{D} 3}$ |
| H | L | L | L | D4 | $\overline{\mathrm{D} 4}$ |
| H | L | H | L | D5 | $\overline{\mathrm{D} 5}$ |
| H | H | L | L | D6 | $\overline{\mathrm{D} 6 ~}$ |
| H | H | H | L | D7 | $\overline{\mathrm{D} 7}$ |

D0,D1...D7=the level of the respective D input
$\mathrm{Z}=$ high-impedance state
$\mathrm{X}=$ don't care

## MAXIMUM RATINGS*

| Symbol | Parameter | Value | Unit |
| :---: | :---: | :---: | :---: |
| $\mathrm{V}_{\text {CC }}$ | DC Supply Voltage (Referenced to GND) | -0.5 to +7.0 | V |
| $\mathrm{V}_{\text {IN }}$ | DC Input Voltage (Referenced to GND) | -0.5 to $\mathrm{V}_{\mathrm{CC}}+0.5$ | V |
| $\mathrm{V}_{\text {OUT }}$ | DC Output Voltage (Referenced to GND) | -0.5 to $\mathrm{V}_{\mathrm{CC}}+0.5$ | V |
| $\mathrm{I}_{\text {IN }}$ | DC Input Current, per Pin | $\pm 20$ | mA |
| $\mathrm{I}_{\text {OUT }}$ | DC Output Sink/Source Current, per Pin | $\pm 50$ | mA |
| $\mathrm{I}_{\mathrm{CC}}$ | DC Supply Current, $\mathrm{V}_{\mathrm{CC}}$ and GND Pins | $\pm 50$ | mA |
| $\mathrm{P}_{\mathrm{D}}$ | Power Dissipation in Still Air, Plastic DIP+ SOIC Package+ | $\begin{aligned} & 750 \\ & 500 \end{aligned}$ | mW |
| Tstg | Storage Temperature | -65 to +150 | ${ }^{\circ} \mathrm{C}$ |
| T | Lead Temperature, 1 mm from Case for 10 Seconds (Plastic DIP or SOIC Package) | 260 | ${ }^{\circ} \mathrm{C}$ |

*Maximum Ratings are those values beyond which damage to the device may occur.
Functional operation should be restricted to the Recommended Operating Conditions.

+ Derating - Plastic DIP: $-10 \mathrm{~mW} /{ }^{\circ} \mathrm{C}$ from $65^{\circ}$ to $125^{\circ} \mathrm{C}$
SOIC Package: : $-7 \mathrm{~mW} /{ }^{\circ} \mathrm{C}$ from $65^{\circ}$ to $125^{\circ} \mathrm{C}$


## RECOMMENDED OPERATING CONDITIONS

| Symbol | Parameter | Min | Max | Unit |
| :---: | :--- | :---: | :---: | :---: |
| $\mathrm{V}_{\mathrm{CC}}$ | DC Supply Voltage (Referenced to GND) | 4.5 | 5.5 | V |
| $\mathrm{~V}_{\mathrm{IN}}, \mathrm{V}_{\mathrm{OUT}}$ | DC Input Voltage, Output Voltage (Referenced to GND) | 0 | $\mathrm{~V}_{\mathrm{CC}}$ | V |
| $\mathrm{T}_{\mathrm{J}}$ | Junction Temperature (PDIP) |  | 140 | ${ }^{\circ} \mathrm{C}$ |
| $\mathrm{T}_{\mathrm{A}}$ | Operating Temperature, All Package Types | -40 | +85 | ${ }^{\circ} \mathrm{C}$ |
| $\mathrm{I}_{\mathrm{OH}}$ | Output Current - High |  | -24 | mA |
| $\mathrm{I}_{\mathrm{OL}}$ | Output Current - Low |  | 24 | mA |
| $\mathrm{t}_{\mathrm{r}}, \mathrm{t}_{\mathrm{f}}$ | Input Rise and Fall Time <br>  <br> (except Schmitt Inputs) | $\mathrm{V}_{\mathrm{CC}}=4.5 \mathrm{~V}$ | 0 | 10 |
| $\mathrm{~ns} / \mathrm{V}$ |  |  |  |  |

* $\mathrm{V}_{\text {IN }}$ from 0.8 V to 2.0 V

This device contains protection circuitry to guard against damage due to high static voltages or electric fields. However, precautions must be taken to avoid applications of any voltage higher than maximum rated voltages to this high-impedance circuit. For proper operation, $\mathrm{V}_{\text {IN }}$ and $\mathrm{V}_{\text {Out }}$ should be constrained to the range GND $\leq\left(\mathrm{V}_{\text {IN }}\right.$ or $\left.\mathrm{V}_{\text {OUT }}\right) \leq \mathrm{V}_{\text {CC }}$.

Unused inputs must always be tied to an appropriate logic voltage level (e.g., either GND or $\mathrm{V}_{\mathrm{CC}}$ ). Unused outputs must be left open.

DC ELECTRICAL CHARACTERISTICS(Voltages Referenced to GND)

| Symbol | Parameter | Test Conditions | $\begin{gathered} \mathrm{V}_{\mathrm{CC}} \\ \mathrm{~V} \end{gathered}$ | Guaranteed Limits |  | Unit |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: |
|  |  |  |  | $25^{\circ} \mathrm{C}$ | $\begin{gathered} -40^{\circ} \mathrm{C} \text { to } \\ 85^{\circ} \mathrm{C} \end{gathered}$ |  |
| $\mathrm{V}_{\text {IH }}$ | Minimum High-Level Input Voltage | $\mathrm{V}_{\text {OUT }}=0.1 \mathrm{~V}$ or $\mathrm{V}_{\text {CC }}-0.1 \mathrm{~V}$ | $\begin{aligned} & \hline 4.5 \\ & 5.5 \\ & \hline \end{aligned}$ | $\begin{array}{l\|} \hline 2.0 \\ 2.0 \\ \hline \end{array}$ | $\begin{aligned} & 2.0 \\ & 2.0 \\ & \hline \end{aligned}$ | V |
| $\mathrm{V}_{\text {IL }}$ | Maximum Low Level Input Voltage | $\mathrm{V}_{\text {OUT }}=0.1 \mathrm{~V}$ or $\mathrm{V}_{\text {CC }}-0.1 \mathrm{~V}$ | $\begin{aligned} & 4.5 \\ & 5.5 \end{aligned}$ | $\begin{aligned} & 0.8 \\ & 0.8 \end{aligned}$ | $\begin{aligned} & 0.8 \\ & 0.8 \end{aligned}$ | V |
| $\mathrm{V}_{\mathrm{OH}}$ | Minimum High-Level Output Voltage | $\mathrm{I}_{\text {OUt }} \leq-50 \mu \mathrm{~A}$ | $\begin{aligned} & 4.5 \\ & 5.5 \\ & \hline \end{aligned}$ | $\begin{gathered} 4.4 \\ 5.4 \\ \hline \end{gathered}$ | $\begin{aligned} & 4.4 \\ & 5.4 \end{aligned}$ | V |
|  |  | $\begin{aligned} & { }^{*} \mathrm{~V}_{\mathrm{IN}}=\mathrm{V}_{\mathrm{IH}} \text { or } \mathrm{V}_{\mathrm{IL}} \\ & \mathrm{I}_{\mathrm{OH}}=-24 \mathrm{~mA} \\ & \mathrm{I}_{\mathrm{OH}}=-24 \mathrm{~mA} \\ & \hline \end{aligned}$ | $\begin{aligned} & 4.5 \\ & 5.5 \end{aligned}$ | $\begin{aligned} & 3.86 \\ & 4.86 \end{aligned}$ | $\begin{aligned} & 3.76 \\ & 4.76 \end{aligned}$ |  |
| $\mathrm{V}_{\text {OL }}$ | Maximum Low-Level Output Voltage | $\mathrm{I}_{\text {OUT }} \leq 50 \mu \mathrm{~A}$ | $\begin{aligned} & 4.5 \\ & 5.5 \end{aligned}$ | $\begin{aligned} & 0.1 \\ & 0.1 \end{aligned}$ | $\begin{aligned} & 0.1 \\ & 0.1 \end{aligned}$ | V |
|  |  | $\begin{aligned} & { }^{*} \mathrm{~V}_{\mathrm{IN}}=\mathrm{V}_{\mathrm{IH}} \text { or } \mathrm{V}_{\mathrm{IL}} \\ & \mathrm{I}_{\mathrm{OL}}=24 \mathrm{~mA} \\ & \mathrm{I}_{\mathrm{OL}}=24 \mathrm{~mA} \end{aligned}$ | $\begin{aligned} & 4.5 \\ & 5.5 \end{aligned}$ | $\begin{aligned} & 0.36 \\ & 0.36 \\ & \hline \end{aligned}$ | $\begin{aligned} & 0.44 \\ & 0.44 \end{aligned}$ |  |
| $\mathrm{I}_{\text {IN }}$ | Maximum Input Leakage Current | $\mathrm{V}_{\text {IN }}=\mathrm{V}_{\text {CC }}$ or GND | 5.5 | $\pm 0.1$ | $\pm 1.0$ | $\mu \mathrm{A}$ |
| $\Delta \mathrm{I}_{\text {CCT }}$ | Additional Max. $\mathrm{I}_{\mathrm{CC}} /$ Input | $\mathrm{V}_{\mathrm{IN}}=\mathrm{V}_{\text {CC }}-2.1 \mathrm{~V}$ | 5.5 |  | 1.5 | mA |
| $\mathrm{I}_{\mathrm{OZ}}$ | Maximum Three- <br> State Leakage <br> Current | $\begin{aligned} & \mathrm{V}_{\mathrm{IN}}(\mathrm{OE})=\mathrm{V}_{\mathrm{IH}} \text { or } \mathrm{V}_{\mathrm{IL}} \\ & \mathrm{~V}_{\mathrm{IN}}=\mathrm{V}_{\mathrm{CC}} \text { or } \mathrm{GND} \\ & \mathrm{~V}_{\mathrm{OUT}}=\mathrm{V}_{\mathrm{CC}} \text { or } \mathrm{GND} \\ & \hline \end{aligned}$ | 5.5 | $\pm 0.5$ | $\pm 5.0$ | $\mu \mathrm{A}$ |
| $\mathrm{I}_{\text {OLD }}$ | +Minimum Dynamic Output Current | $\mathrm{V}_{\text {OLD }}=1.65 \mathrm{~V}$ Max | 5.5 |  | 75 | mA |
| $\mathrm{I}_{\text {OHD }}$ | +Minimum Dynamic Output Current | $\mathrm{V}_{\mathrm{OHD}}=3.85 \mathrm{~V}$ Min | 5.5 |  | -75 | mA |
| $\mathrm{I}_{\mathrm{CC}}$ | Maximum Quiescent Supply Current (per Package) | $\mathrm{V}_{\text {IN }}=\mathrm{V}_{\text {CC }}$ or GND | 5.5 | 8.0 | 80 | $\mu \mathrm{A}$ |

[^0]AC ELECTRICAL CHARACTERISTICS $\left(\mathrm{V}_{\mathrm{CC}}=5.0 \mathrm{~V} \pm 10 \%, \mathrm{C}_{\mathrm{L}}=50 \mathrm{pF}\right.$, Input $\left.\mathrm{t}_{\mathrm{r}}=\mathrm{t}_{\mathrm{f}}=3.0 \mathrm{~ns}\right)$

| Symbol | Parameter | Guaranteed Limits |  |  |  | Unit |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: |
|  |  | $25^{\circ} \mathrm{C}$ |  | $-40^{\circ} \mathrm{C}$ to $85^{\circ} \mathrm{C}$ |  |  |
|  |  | Min | Max | Min | Max |  |
| $\mathrm{t}_{\text {PLH }}$ | Propagation Delay, Input A to Output Y or Y (Figure 3) | 2.5 | 15.5 | 2.0 | 17.0 | ns |
| $\mathrm{t}_{\text {PHL }}$ | Propagation Delay, Input A to Output Y or Y (Figure 3) | 2.5 | 16.5 | 2.5 | 18.5 | ns |
| $\mathrm{t}_{\text {PLH }}$ | Propagation Delay, Input D to Output Y or Y (Figures 1,2) | 2.5 | 12.0 | 2.0 | 13.0 | ns |
| $\mathrm{t}_{\text {PHL }}$ | Propagation Delay, Input D to Output Y or Y (Figures 1,2) | 2.5 | 12.5 | 2.5 | 14.0 | ns |
| $\mathrm{t}_{\text {PZH }}$ | Propagation Delay, Output Enable to Output Y or Y (Figure 4) | 1.5 | 8.5 | 1.5 | 9.0 | ns |
| $\mathrm{t}_{\text {PZL }}$ | Propagation Delay, Output Enable to Output Y or Y (Figure 4) | 1.5 | 8.5 | 1.5 | 9.5 | ns |
| $\mathrm{t}_{\text {PHZ }}$ | Propagation Delay, Output Enable to Output Y or Y (Figure 4) | 2.0 | 12.0 | 2.0 | 13.0 | ns |
| $\mathrm{t}_{\text {PLZ }}$ | Propagation Delay, Output Enable to Output Y or Y (Figure 4) | 1.5 | 8.5 | 1.5 | 9.0 | ns |
| $\mathrm{C}_{\text {IN }}$ | Maximum Input Capacitance | 4.5 |  | 4.5 |  | pF |


|  |  | Typical @25 ${ }^{\circ} \mathrm{C}, \mathrm{V}_{\mathrm{CC}}=5.0 \mathrm{~V}$ |  |
| :---: | :---: | :---: | :---: |
| $\mathrm{C}_{\mathrm{PD}}$ | Power Dissipation Capacitance | 70 | pF |



Figure 1. Switching Waveforms


Figure 2. Switching Waveforms


Figure 3. Switching Waveforms


Figure 4. Switching Waveforms

EXPANDED LOGIC DIAGRAM



[^0]:    * All outputs loaded; thresholds on input associated with output under test.
    +Maximum test duration 2.0 ms , one output loaded at a time.

